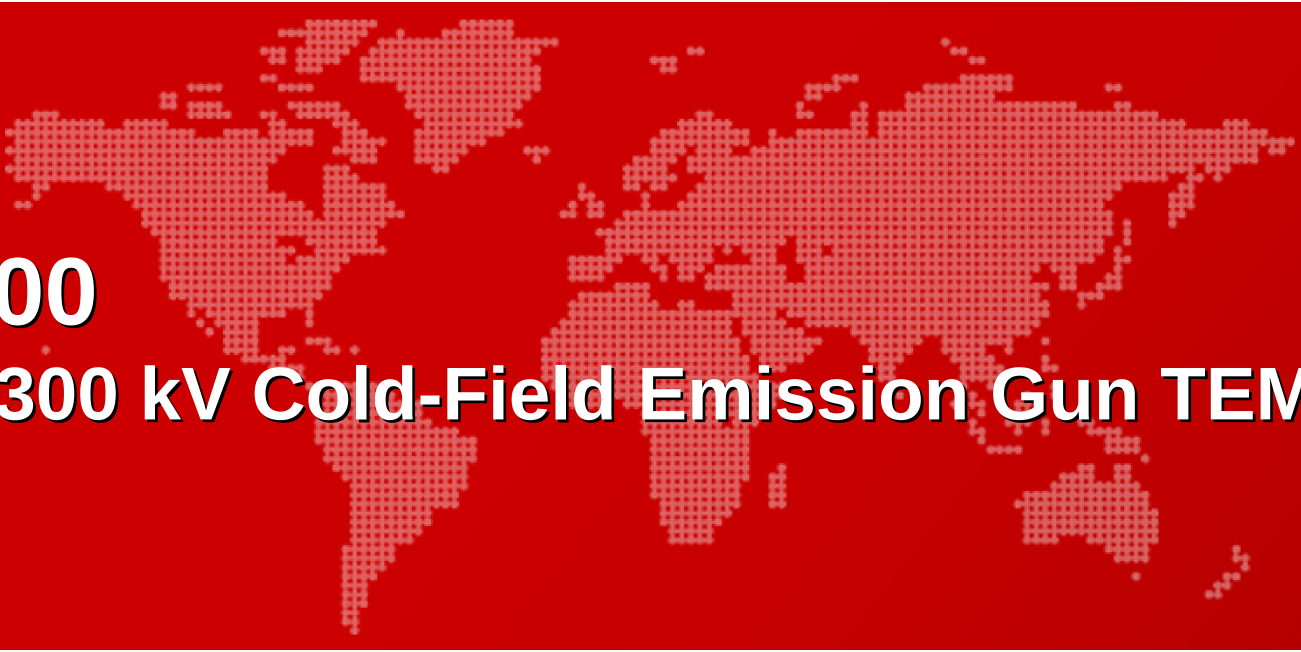


HF-3300

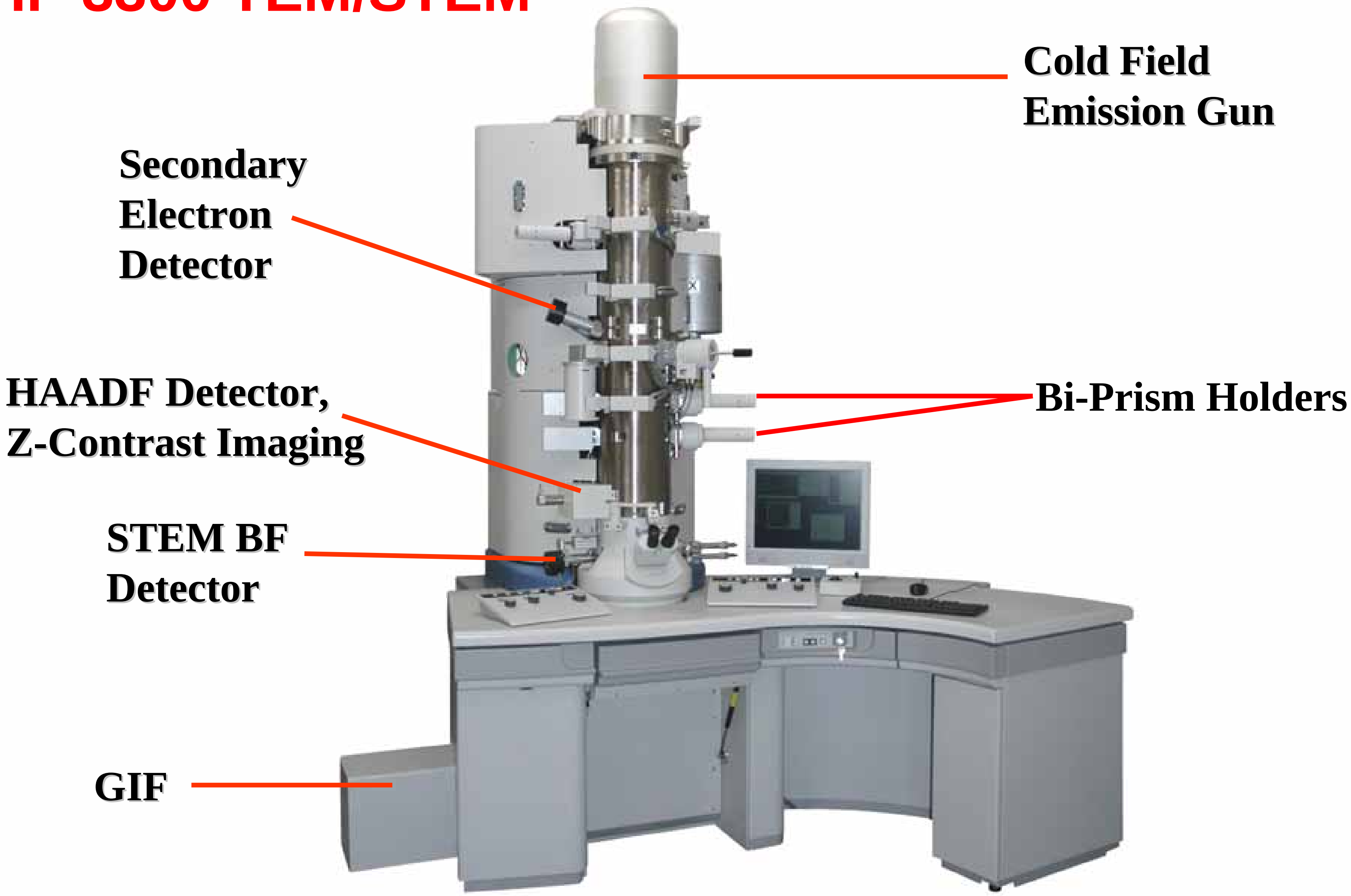
Hitachi 300 kV Cold-Field Emission Gun TEM/STEM

Powerful analytical and high resolution TEM/STEM

with inherent high beam brightness, high coherence,

high energy resolution, and Hitachi unique functions!

HF-3300 TEM/STEM



Excellent New Functions

1. High energy-resolution and high beam current.
2. Parallel nanobeam electron diffraction for high precision stress analysis.
3. Spatially-resolved EELS for instant multipoint compositional and chemical binding state analyses.
4. Double-biprism electron holography for dopant mapping and magnetic and dielectric materials study.
5. Real-time 3D structural and chemical characterization using Hitachi 3D sample holder.
6. Built-in STEM, and simultaneous signal collections: HAADF/BF, HAADF/SE, SE/BF, HAADF/EELS.

Compatible Sample Holders for Hitachi Tools

300kV FE-TEM

FB-2100 FIB

Compatible holder

HD-2300 STEM

Comments and detailed information? Please contact:

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